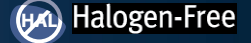
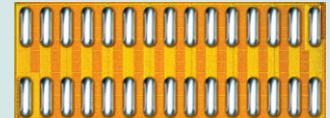


EPC2020 – Enhancement Mode Power Transistor

 V_{DS} , 60 V $R_{DS(on)}$, 2.2 mΩ I_D , 90 A

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low $R_{DS(on)}$, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR} . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Maximum Ratings			
PARAMETER		VALUE	UNIT
V_{DS}	Drain-to-Source Voltage (Continuous)	60	V
	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	72	
I_D	Continuous ($T_A = 25^\circ\text{C}$, $R_{\theta JA} = 7^\circ\text{C/W}$)	90	A
	Pulsed (25°C, $T_{PULSE} = 300 \mu\text{s}$)	470	
V_{GS}	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
T_J	Operating Temperature	-40 to 150	°C
T_{STG}	Storage Temperature	-40 to 150	



EPC2020 eGaN® FETs are supplied only in passivated die form with solder bumps.
Die Size: 6.05 mm x 2.3 mm

- High Speed DC-DC Conversion
- Motor Drive
- Industrial Automation
- Synchronous Rectification
- Inrush Protection
- Class-D Audio

Thermal Characteristics			
PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.4	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	1.1	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	42	

Note 1: $R_{\theta JA}$ is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board.
See https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf for details.

Static Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
BV_{DSS}	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}$, $I_D = 1.1 \text{ mA}$	60			V
I_{DSS}	Drain-Source Leakage	$V_{GS} = 48 \text{ V}$, $V_{DS} = 0 \text{ V}$		0.1	0.8	mA
I_{GSS}	Gate-to-Source Forward Leakage	$V_{GS} = 5 \text{ V}$		1	9	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 \text{ V}$		0.1	0.8	mA
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 16 \text{ mA}$	0.8	1.4	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}$, $I_D = 31 \text{ A}$		1.5	2.2	mΩ
V_{SD}	Source-Drain Forward Voltage	$I_S = 0.5 \text{ A}$, $V_{GS} = 0 \text{ V}$		1.6		V

All measurements were done with substrate connected to source.

Dynamic Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C_{ISS}	Input Capacitance	$V_{DS} = 30\text{ V}, V_{GS} = 0\text{ V}$		1780	2140	pF
C_{OSS}	Output Capacitance			1020	1530	
C_{RSS}	Reverse Transfer Capacitance			24		
$C_{OSS(ER)}$	Effective Output Capacitance, Energy Related (Note 2)	$V_{DS} = 0\text{ to }30\text{ V}, V_{GS} = 0\text{ V}$		1410		pF
$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 3)			1660		
R_G	Gate Resistance			0.3		Ω
Q_G	Total Gate Charge	$V_{DS} = 30\text{ V}, V_{GS} = 5\text{ V}, I_D = 31\text{ A}$		16	20	nC
Q_{GS}	Gate-to-Source Charge	$V_{DS} = 30\text{ V}, I_D = 31\text{ A}$		3.9		
Q_{GD}	Gate-to-Drain Charge			2.3		
$Q_{G(TH)}$	Gate Charge at Threshold			2.8		
Q_{OSS}	Output Charge	$V_{DS} = 30\text{ V}, V_{GS} = 0\text{ V}$		50	75	
Q_{RR}	Source-Drain Recovery Charge			0		

All measurements were done with substrate connected to source.

Note 2: $C_{OSS(ER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} .

Note 3: $C_{OSS(TR)}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} .

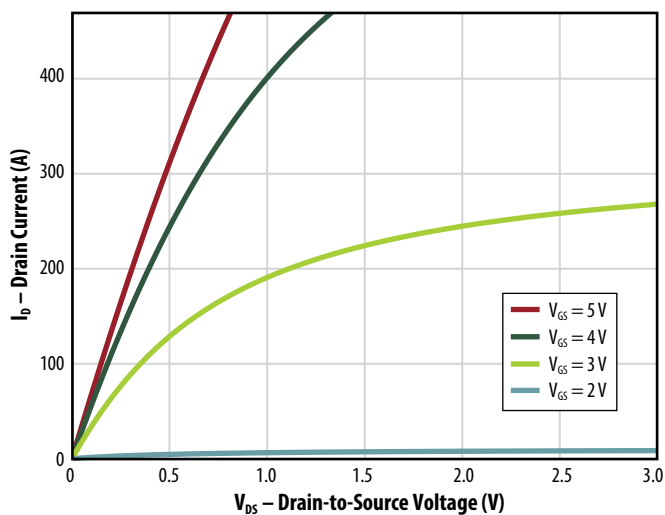
Figure 1: Typical Output Characteristics at 25°C 

Figure 2: Transfer Characteristics

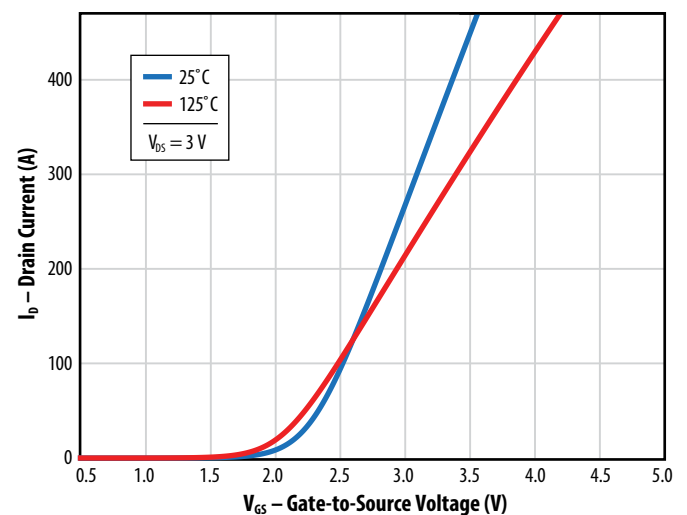
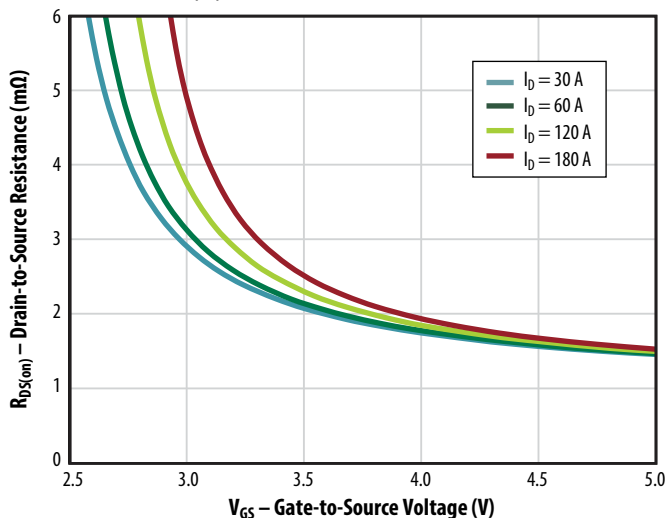
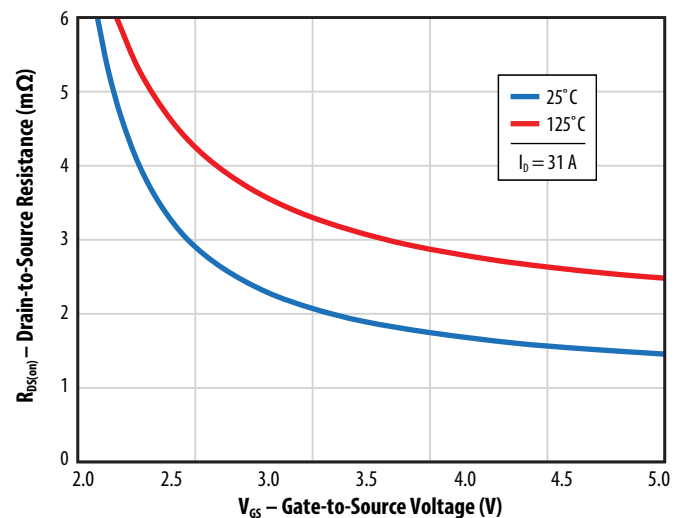
Figure 3: $R_{DS(on)}$ vs. V_{GS} for Various Drain CurrentsFigure 4: $R_{DS(on)}$ vs. V_{GS} for Various Temperatures

Figure 5a: Capacitance (Linear Scale)

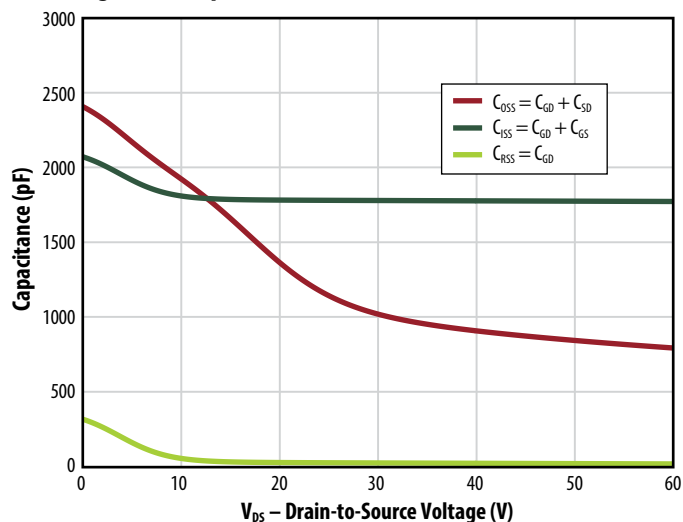


Figure 5b: Capacitance (Log Scale)

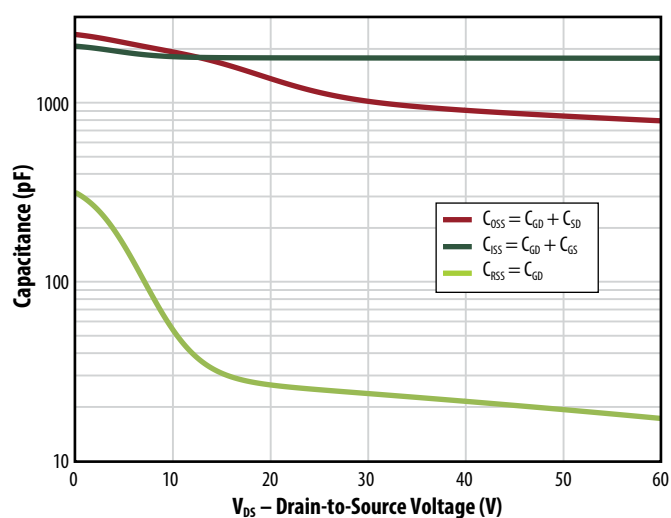


Figure 6: Gate Charge

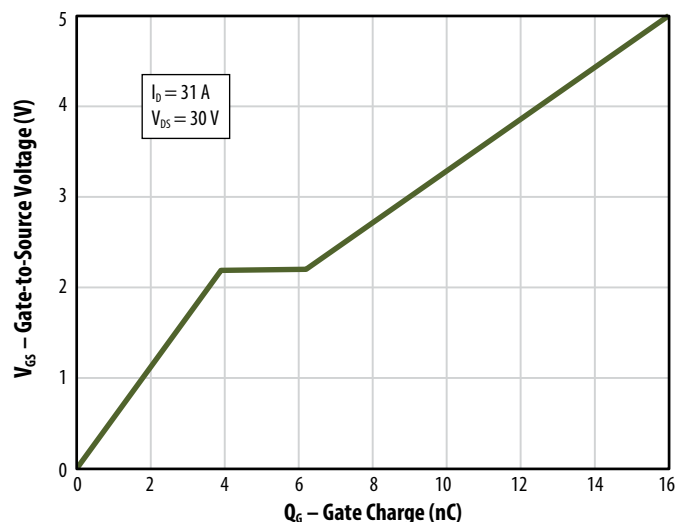


Figure 7: Reverse Drain-Source Characteristics

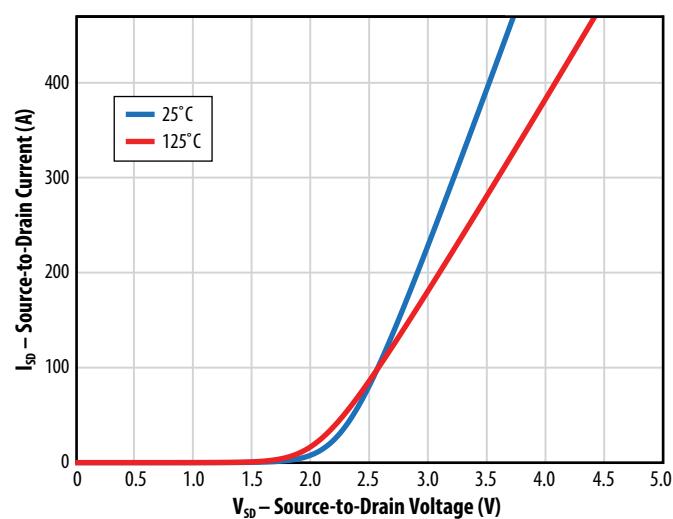


Figure 8: Normalized On-State Resistance vs. Temperature

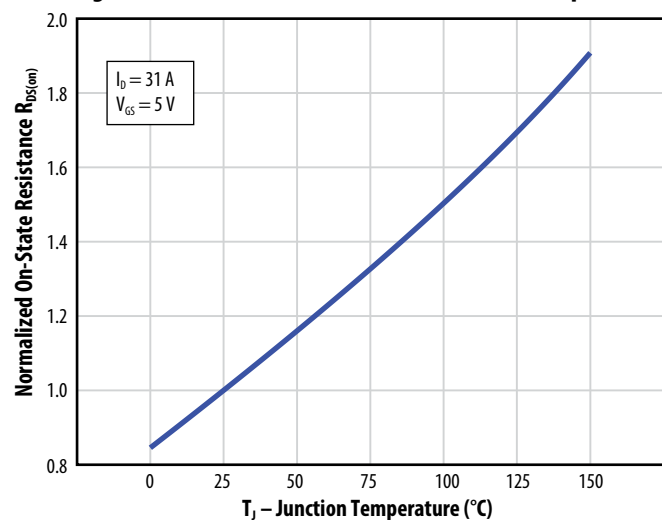
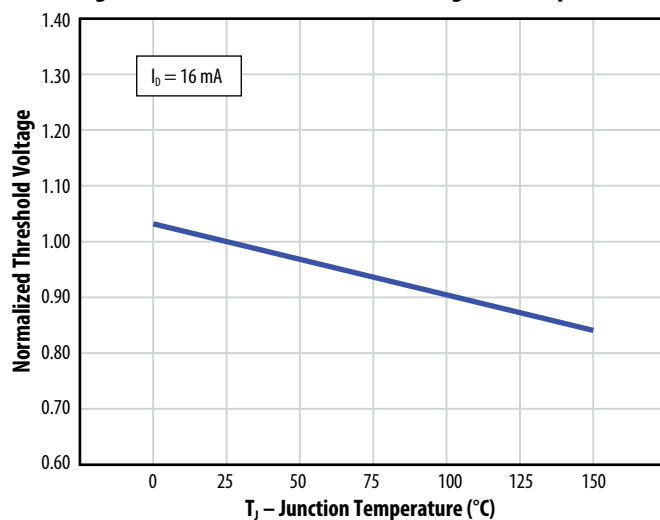


Figure 9: Normalized Threshold Voltage vs. Temperature



All measurements were done with substrate shorted to source.

Figure 10: Gate Leakage Current

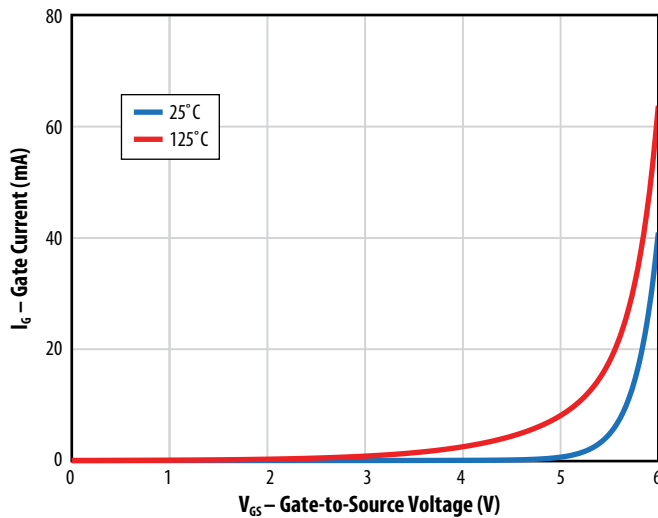


Figure 11: Safe Operating Area

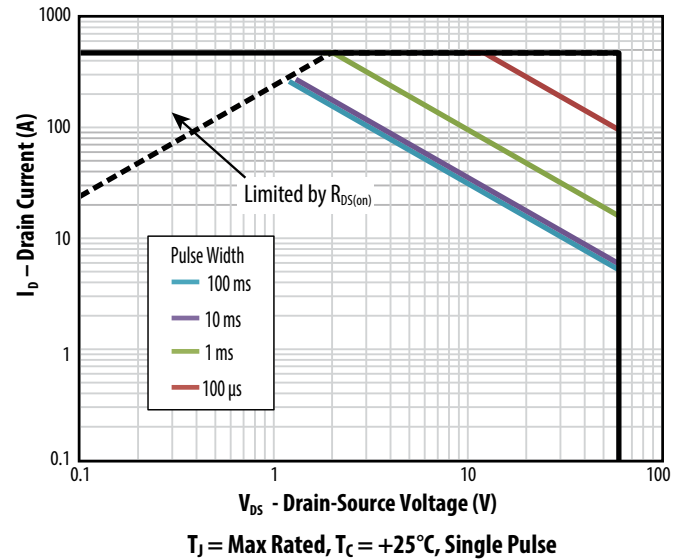
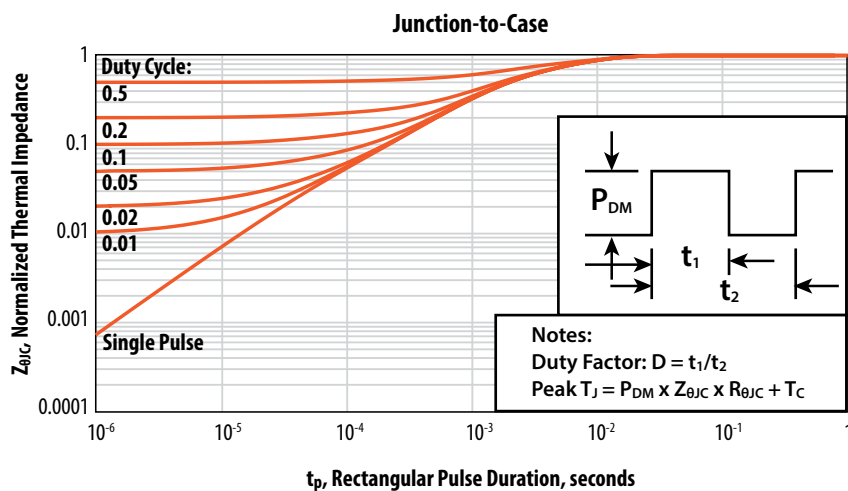
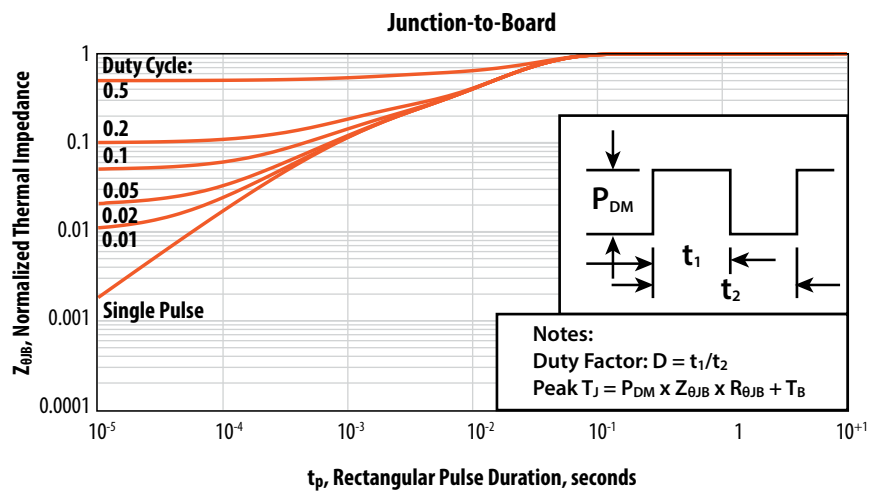
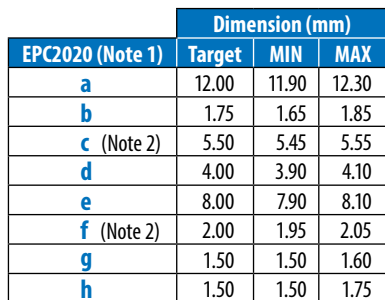


Figure 12: Transient Thermal Response Curves



8 mm pitch, 12 mm wide tape on 7" reel



Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

2020

YYYY

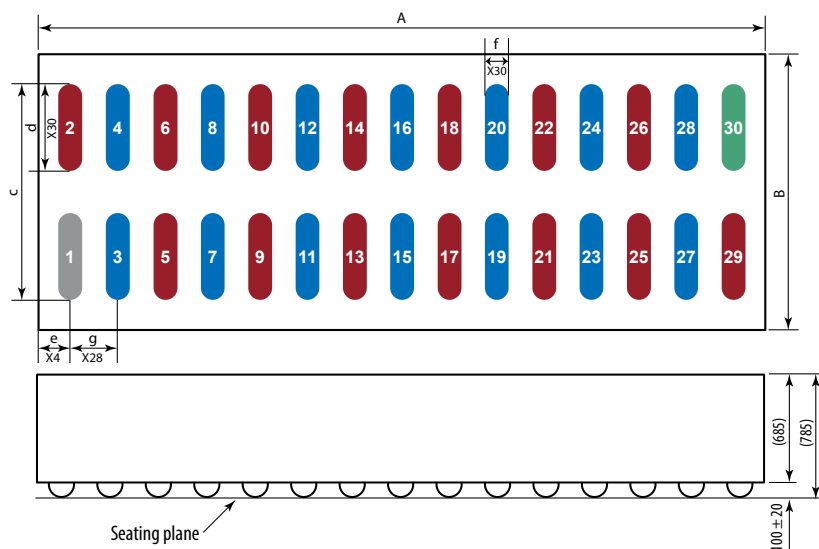
ZZZZ

Die orientation dot

Gate Pad bump is under this corner

Part Number	Laser Markings		
	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3
EPC2020	2020	YYYY	ZZZZ

Solder Bump View

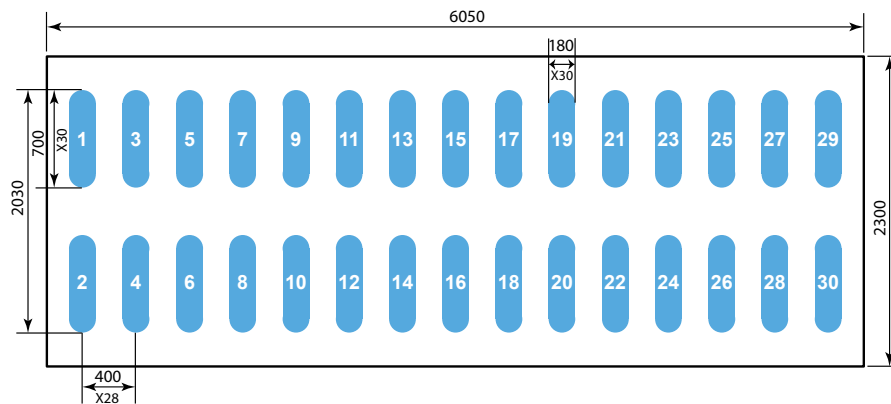


DIM	Micrometers		
	MIN	Nominal	MAX
A	6020	6050	6080
B	2270	2300	2330
c	2047	2050	2053
d	717	720	723
e	210	225	240
f	195	200	205
a	400	400	400

Pad 30 is Substrate.*

*Substrate pin should be connected to Source

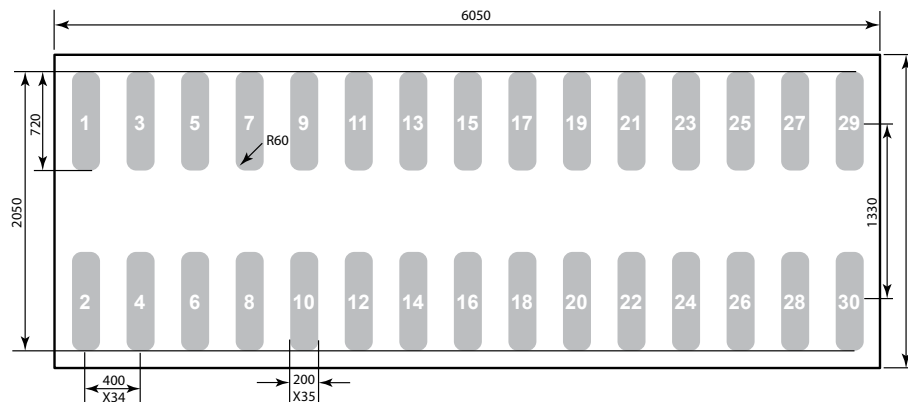
(units in μm)



Pad 1 is Gate;
Pads 2, 5, 6, 9, 10, 13, 14, 17, 18, 21, 22,
25, 26, 29 are Source;
Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23,
24, 27, 28 are Drain;
Pad 30 is Substrate.*

*Substrate pin should be connected to Source

(units in μm)



Additional assembly resources available at
[https://epc-co.com/epc/DesignSupport/
AssemblyBasics.aspx](https://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx)

Information subject to
change without notice.
Revised June, 2020